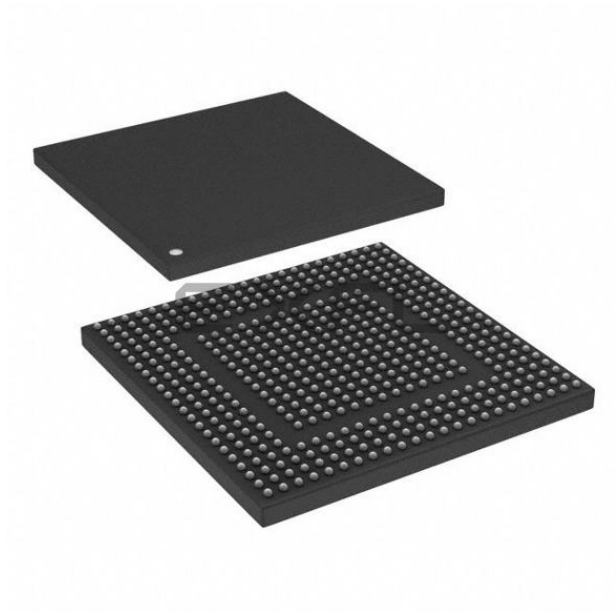

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e300c3
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	400MHz
Co-Processors/DSP	-
RAM Controllers	DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (3)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	473-LFBGA
Supplier Device Package	473-MAPBGA (19x19)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8308czqagda

Table 18. DDR2 SDRAM Output AC Timing Specifications (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
MDQ//MDM/MECC output setup with respect to MDQS	t_{DDKHDS}, t_{DDKLDS}		—	ps	5
266 MHz		900			
MDQ//MDM/MECC output hold with respect to MDQS	t_{DDKHDX}, t_{DDKLDX}		—	ps	5
266 MHz		1100			
MDQS preamble start	t_{DDKHMP}	0.75 x t_{MCK}	—	ns	6
MDQS epilogue end	t_{DDKHME}	0.4 x t_{MCK}	0.6 x t_{MCK}	ns	6

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/$\overline{\text{MCK}}$ referenced measurements are made from the crossing of the two signals ±0.1 V.
3. ADDR/CMD includes all DDR SDRAM output signals except MCK/$\overline{\text{MCK}}$, $\overline{\text{MCS}}$, and MDQ/MECC/MDM/MDQS.
4. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK[n] clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the DQSS override bits in the TIMING_CFG_2 register. This is typically set to the same delay as the clock adjust in the CLK_CNTL register. The timing parameters listed in the table assume that these 2 parameters have been set to the same adjustment value. For a description and understanding of the timing modifications enabled by use of these bits, see the *MPC8308 PowerQUICC II Pro Processor Reference Manual*.
5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe should be centered inside of the data eye at the pins of the microprocessor.
6. All outputs are referenced to the rising edge of MCK[n] at the pins of the microprocessor. Note that t_{DDKHMP} follows the symbol conventions described in note 1.

This figure provides the AC test load for the DDR2 bus.

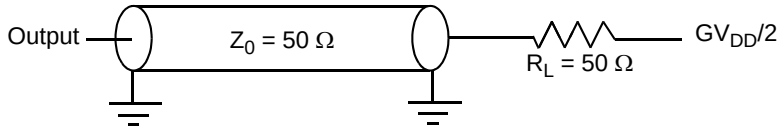


Figure 7. DDR2 AC Test Load

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface.

7.1 DUART DC Electrical Characteristics

This table provides the DC electrical characteristics for the DUART interface.

Table 19. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2.1	NV_{DD} + 0.3	V
Low-level input voltage NVDD	V_{IL}	–0.3	0.8	V
High-level output voltage, I_{OH} = –100 μA	V_{OH}	NV_{DD} – 0.2	—	V
Low-level output voltage, I_{OL} = 100 μA	V_{OL}	—	0.2	V
Input current (0 V ≤V_{IN} ≤ NV_{DD})	I_{IN}	—	± 5	μA

7.2 DUART AC Electrical Specifications

This table provides the AC timing parameters for the DUART interface.

Table 20. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	256	baud	—
Maximum baud rate	> 1,000,000	baud	1
Oversample rate	16	—	2

Notes:
1. Actual attainable baud rate is limited by the latency of interrupt processing.
2. The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

8 Ethernet: Three-Speed Ethernet, MII Management

This section provides the AC and DC electrical characteristics for three-speed, 10/100/1000, and MII management. MPC8308 supports dual Ethernet controllers.

Table 25. RGMII AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD} of 2.5 V ± 5%.

GTX_CLK125 reference clock period	t_{G12} [6]	—	8.0	—	ns
GTX_CLK125 reference clock duty cycle	t_{G125H}/t_{G125}	47	—	53	%

Notes:

1. In general, the clock reference symbol representation for this section is based on the symbols RGT to represent RGMII timing. For example, the subscript of t_{RGT} represents the RGMII receive (RX) clock. Note also that the notation for rise (R) and fall (F) times follows the clock symbol that is being represented. For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (RGT).
2. This implies that PC board design requires clocks to be routed such that an additional trace delay of greater than 1.5 ns is added to the associated clock signal.
3. For 10 and 100 Mbps, t_{RGT} scales to 400 ns ± 40 ns and 40 ns ± 4 ns, respectively.
4. Duty cycle may be stretched/shrunk during speed changes or while transitioning to a received packet's clock domains as long as the minimum duty cycle is not violated and stretching occurs for no more than three t_{RGT} of the lowest speed transitioned between.
5. Duty cycle reference is $0.5*LV_{DD}$
6. This symbol is used to represent the external GTX_CLK125 and does not follow the original symbol naming convention.

This figure shows the RGMII AC timing and multiplexing diagrams.

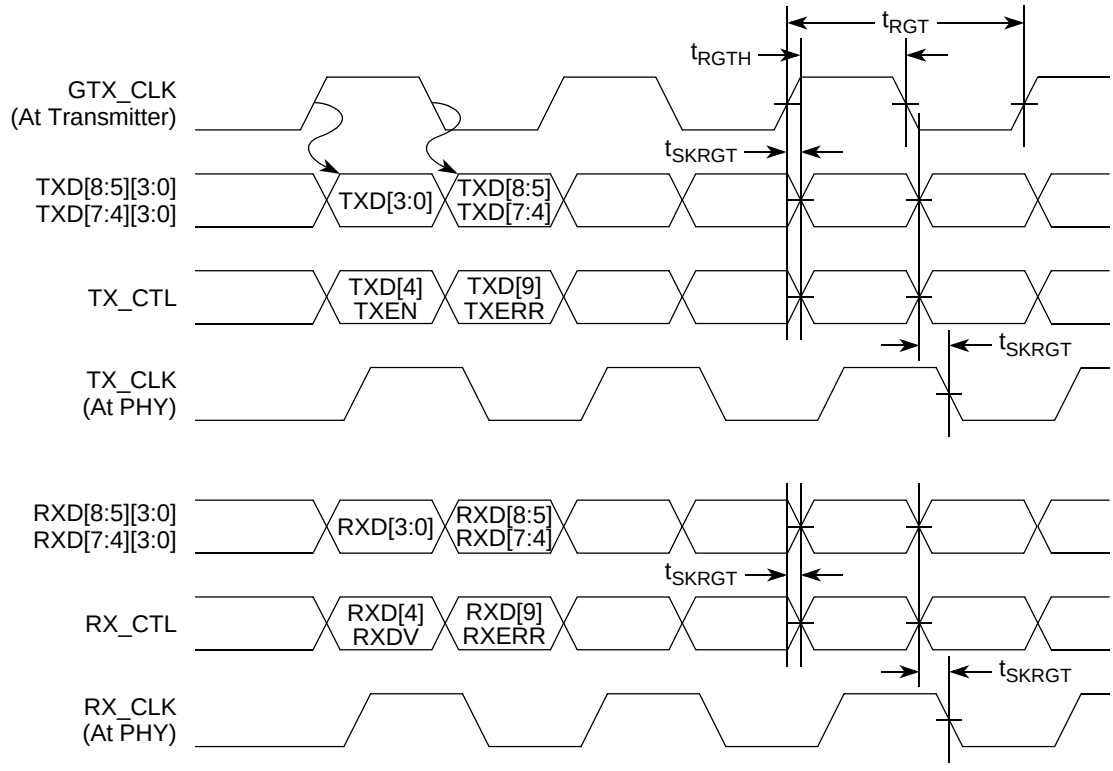


Figure 11. RGMII AC Timing and Multiplexing Diagrams

8.3 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for MII

and RGMII are specified in Section 8.1, "Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—MII/RGMII Electrical Characteristics."

8.3.1 MII Management DC Electrical Characteristics

The MDC and MDIO are defined to operate at a supply voltage of 3.3 V. This table provides the DC electrical characteristics for MDIO and MDC.

Table 26. MII Management DC Electrical Characteristics When Powered at 3.3 V

Parameter	Symbol	Conditions		Min	Max	Unit
Supply voltage (3.3 V)	NV_{DD}	—		3.0	3.6	V
Output high voltage	V_{OH}	I_{OH} = –1.0 mA	NV_{DD} = Min	2.10	NV_{DD} + 0.3	V
Output low voltage	V_{OL}	I_{OL} = 1.0 mA	LV_{DD} = Min	VSS	0.50	V
Input high voltage	V_{IH}	—		2.0	—	V
Input low voltage	V_{IL}	—		—	0.80	V
Input high current	I_{IH}	NV_{DD} = Max	V_{IN} [1] = 2.1 V	—	40	μA
Input low current	I_{IL}	NV_{DD} = Max	V_{IN} = 0.5 V	–600	—	μA

Note:
1. V_{IN}, in this case, represents the LV_{IN} symbol referenced in Table 1 and Table 2.

8.3.2 MII Management AC Electrical Specifications

This table provides the MII management AC timing specifications.

Table 27. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DDA}/LV_{DDB} is 3.3 V ± 0.3V

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	—	2.5	—	MHz	2
MDC period	t_{MDC}	—	400	—	ns	—
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—
MDC to MDIO delay	t_{MDKHDX}	10	—	170	ns	3
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	—
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	—
MDC rise time	t_{MDCR}	—	—	10	ns	—

10.2.2 DC Level Requirement for SerDes Reference Clocks

The DC level requirement for the MPC8308 SerDes reference clock inputs is different depending on the signaling mode used to connect the clock driver chip and SerDes reference clock inputs as described below.

- **Differential Mode**
  - The input amplitude of the differential clock must be between 400 mV and 1600 mV differential peak-peak (or between 200 mV and 800 mV differential peak). In other words, each signal wire of the differential pair must have a single-ended swing less than 800 mV and greater than 200 mV. This requirement is the same for both external DC-coupled or AC-coupled connection.
  - For **external DC-coupled** connection, as described in Section 10.2.1, "SerDes Reference Clock Receiver Characteristics," the maximum average current requirements sets the requirement for average voltage (common mode voltage) to be between 100 mV and 400 mV. Figure 17 shows the SerDes reference clock input requirement for DC-coupled connection scheme.
  - For **external AC-coupled** connection, there is no common mode voltage requirement for the clock driver. Since the external AC-coupling capacitor blocks the DC level, the clock driver and the SerDes reference clock receiver operate in different command mode voltages. The SerDes reference clock receiver in this connection scheme has its common mode voltage set to XCOREVSS. Each signal wire of the differential inputs is allowed to swing below and above the common mode voltage (XCOREVSS). Figure 18 shows the SerDes reference clock input requirement for AC-coupled connection scheme.
- **Single-ended Mode**
  - The reference clock can also be single-ended. The SD_REF_CLK input amplitude (single-ended swing) must be between 400 mV and 800 mV peak-peak (from Vmin to Vmax) with $\overline{\text{SD\_REF\_CLK}}$ either left unconnected or tied to ground.
  - The SD_REF_CLK input average voltage must be between 200 and 400 mV. Figure 19 shows the SerDes reference clock input requirement for single-ended signaling mode.
  - To meet the input amplitude requirement, the reference clock inputs might need to be DC or AC-coupled externally. For the best noise performance, the reference of the clock could be DC or AC-coupled into the unused phase ($\overline{\text{SD\_REF\_CLK}}$) through the same source impedance as the clock input (SD_REF_CLK) in use.

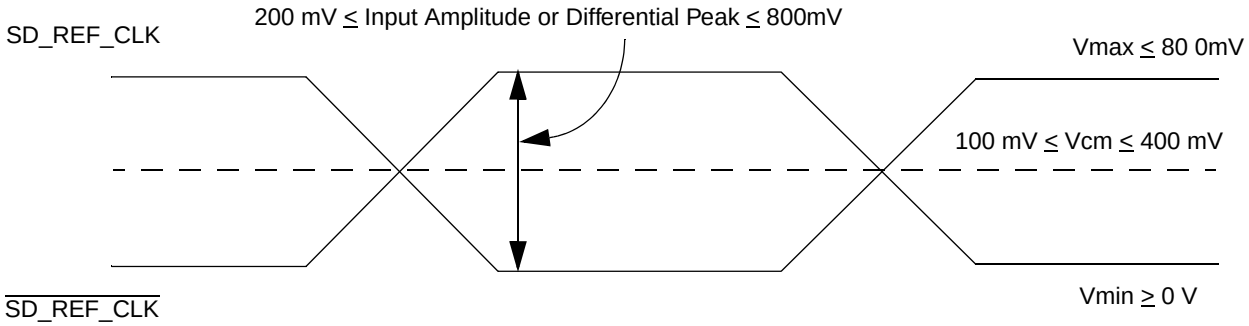


Figure 17. Differential Reference Clock Input DC Requirements (External DC-Coupled)

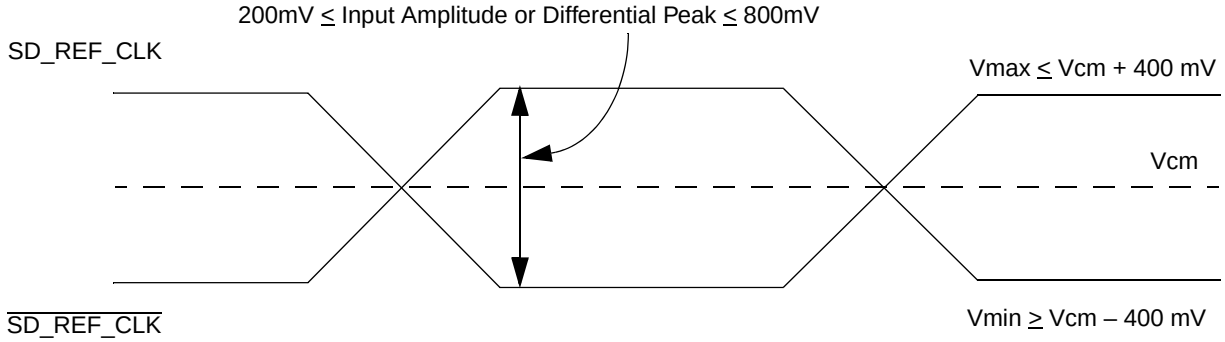


Figure 18. Differential Reference Clock Input DC Requirements (External AC-Coupled)

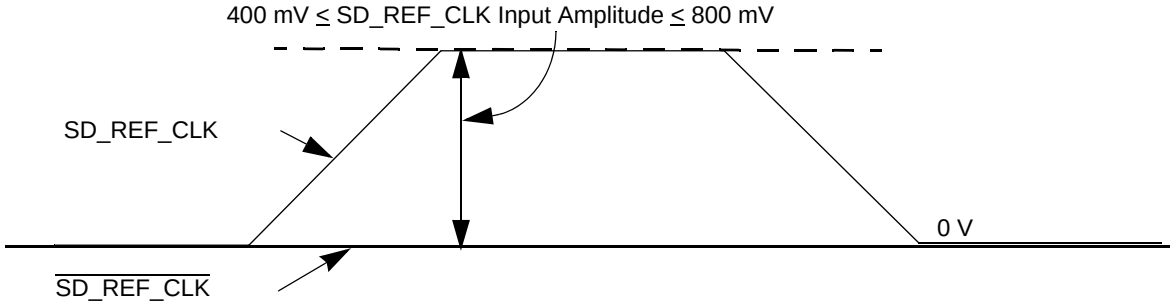


Figure 19. Single-Ended Reference Clock Input DC Requirements

10.2.3 Interfacing with Other Differential Signaling Levels

With on-chip termination to XCOREVSS, the differential reference clocks inputs are high-speed current steering logic (HCSL) compatible and DC coupled.

Many other low voltage differential type outputs like low-voltage differential signaling (LVDS) can be used but may need to be AC-coupled due to the limited common mode input range allowed (100–400 mV) for DC-coupled connection.

LVPECL outputs can produce signal with too large amplitude and may need to be DC-biased at clock driver output first, then followed with series attenuation resistor to reduce the amplitude, in addition to AC-coupling.

11.3 Clocking Dependencies

The ports on the two ends of a link must transmit data at a rate that is within 600 parts per million (ppm) of each other at all times. This is specified to allow bit rate clock sources with a ±300 ppm tolerance.

11.4 Physical Layer Specifications

Following is a summary of the specifications for the physical layer of PCI Express on this device. For further details as well as the specifications of the transport and data link layer please use the *PCI Express Base Specification*, Rev. 1.0a.

11.4.1 Differential Transmitter (TX) Output

This table defines the specifications for the differential output at all transmitters (TXs). The parameters are specified at the component pins.

Table 34. Differential Transmitter (TX) Output Specifications

Parameter	Symbol	Comments	Min	Typical	Max	Units	Note
Unit interval	UI	Each U_{PETX} is 400 ps ± 300 ppm. U_{PETX} does not account for Spread Spectrum Clock dictated variations.	399.88	400	400.12	ps	1
Differential peak-to-peak output voltage	$V_{TX-DIFFp-p}$	$V_{PEDPPTX} = 2*\|V_{TX-D+} - V_{TX-D-}\|$	0.8	—	1.2	V	2
De-Emphasized differential output voltage (ratio)	$V_{TX-DE-RATIO}$	Ratio of the $V_{PEDPPTX}$ of the second and following bits after a transition divided by the $V_{PEDPPTX}$ of the first bit after a transition.	–3.0	–3.5	–4.0	dB	2
Minimum TX eye width	T_{TX-EYE}	The maximum Transmitter jitter can be derived as $T_{TX-MAX-JITTER} = 1 - U_{PEEWTX} = 0.3$ UI.	0.70	—	—	UI	2, 3
Maximum time between the jitter median and maximum deviation from the median	$T_{TX-EYE-MEDIAN-to-MAX-JITTER}$	Jitter is defined as the measurement variation of the crossing points ($V_{PEDPPTX}$ = 0 V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.	—	—	0.15	UI	2, 3
D+/D- TX output rise/fall time	$T_{TX-RISE}$, $T_{TX-FALL}$	—	0.125	—	—	UI	2, 5
RMS AC peak common mode output voltage	$V_{TX-CM-ACp}$	$V_{PEACPCMTX} = RMS(\|V_{TXD+} + V_{TXD-}\|/2 - V_{TX-CM-DC})$ $V_{TX-CM-DC} = DC_{(avg)}$ of $\|V_{TX-D+} + V_{TX-D-}\|/2$	—	—	20	mV	2

Table 34. Differential Transmitter (TX) Output Specifications (continued)

Parameter	Symbol	Comments	Min	Typical	Max	Units	Note
AC coupling capacitor	C_{TX}	All Transmitters shall be AC coupled. The AC coupling is required either within the media or within the transmitting component itself. An external capacitor of 100nF is recommended.	75	—	200	nF	—
Crosslink random timeout	$T_{crosslink}$	This random timeout helps resolve conflicts in crosslink configuration by eventually resulting in only one Downstream and one Upstream Port.	0	—	1	ms	7

Notes:
1. No test load is necessarily associated with this value.
2. Specified at the measurement point into a timing and voltage compliance test load as shown in Figure 29 and measured over any 250 consecutive TX UIs. (Also refer to the transmitter compliance eye diagram shown in Figure 27.)
3. A T_{TX-EYE} = 0.70 UI provides for a total sum of deterministic and random jitter budget of $T_{TX-JITTER-MAX}$ = 0.30 UI for the transmitter collected over any 250 consecutive TX UIs. The $T_{TX-EYE-MEDIAN-to-MAX-JITTER}$ median is less than half of the total TX jitter budget collected over any 250 consecutive TX UIs. It should be noted that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value.
4. The transmitter input impedance shall result in a differential return loss greater than or equal to 12 dB and a common mode return loss greater than or equal to 6 dB over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements is 50 Ω to ground for both the D+ and D– line (that is, as measured by a vector network analyzer with 50-Ω probes, see Figure 29). Note that the series capacitors, C_{TX}, is optional for the return loss measurement.
5. Measured between 20%–80% at transmitter package pins into a test load as shown in Figure 29 for both V_{TX-D+} and V_{TX-D-}.
6. See Section 4.3.1.8 of the *PCI Express Base Specifications*, Rev 1.0a.
7. See Section 4.2.6.3 of the *PCI Express Base Specifications*, Rev 1.0a.

11.4.2 Transmitter Compliance Eye Diagrams

The TX eye diagram in Figure 27 is specified using the passive compliance/test measurement load (Figure 29) in place of any real PCI Express interconnect + RX component. There are two eye diagrams that must be met for the transmitter. Both diagrams must be aligned in time using the jitter median to locate the center of the eye diagram. The different eye diagrams differ in voltage depending on whether it is a transition bit or a de-emphasized bit. The exact reduced voltage level of the de-emphasized bit is always relative to the transition bit.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

It is recommended that the recovered TX UI be calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function (that is, least squares and median deviation fits).

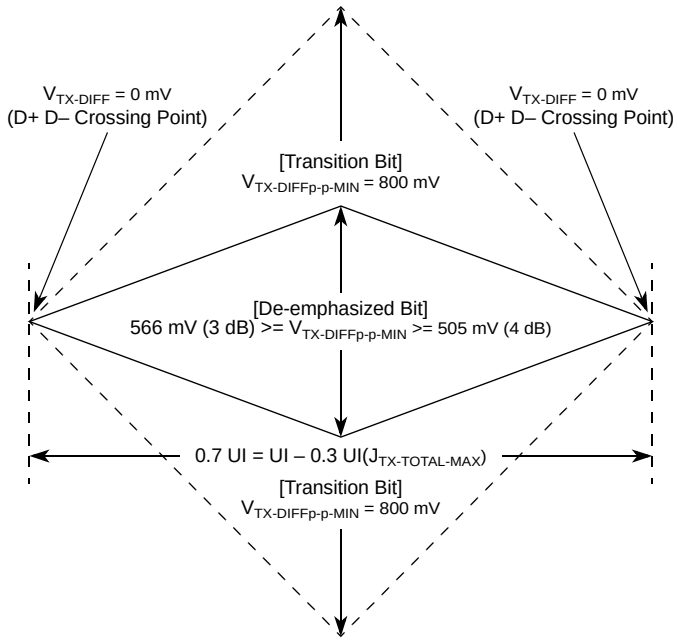


Figure 27. Minimum Transmitter Timing and Voltage Output Compliance Specifications

11.4.3 Differential Receiver (RX) Input Specifications

This table defines the specifications for the differential input at all receivers (RXs). The parameters are specified at the component pins.

Table 35. Differential Receiver (RX) Input Specifications

Parameter	Symbol	Comments	Min	Typical	Max	Units	Note
Unit interval	UI	Each U_{PERX} is 400 ps ± 300 ppm. U_{PERX} does not account for Spread Spectrum Clock dictated variations.	399.88	400	400.12	ps	1
Differential peak-to-peak output voltage	$V_{RX-DIFFp-p}$	$V_{PEDPPRX} = 2*\|V_{RX-D+} - V_{RX-D-}\|$	0.175	—	1.200	V	2
Minimum receiver eye width	T_{RX-EYE}	The maximum interconnect media and Transmitter jitter that can be tolerated by the Receiver can be derived as $T_{RX-MAX-JITTER} = 1 - U_{PEEWRX} = 0.6$ UI.	0.4	—	—	UI	2, 3
Maximum time between the jitter median and maximum deviation from the median.	$T_{RX-EYE-MEDIAN-to-MAX-JITTER}$	Jitter is defined as the measurement variation of the crossing points ($V_{PEDPPRX}$ = 0 V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.	—	—	0.3	UI	2, 3, 7

13.2.2 Full Speed Input Path (Read)

This figure provides the data and command input timing diagram.

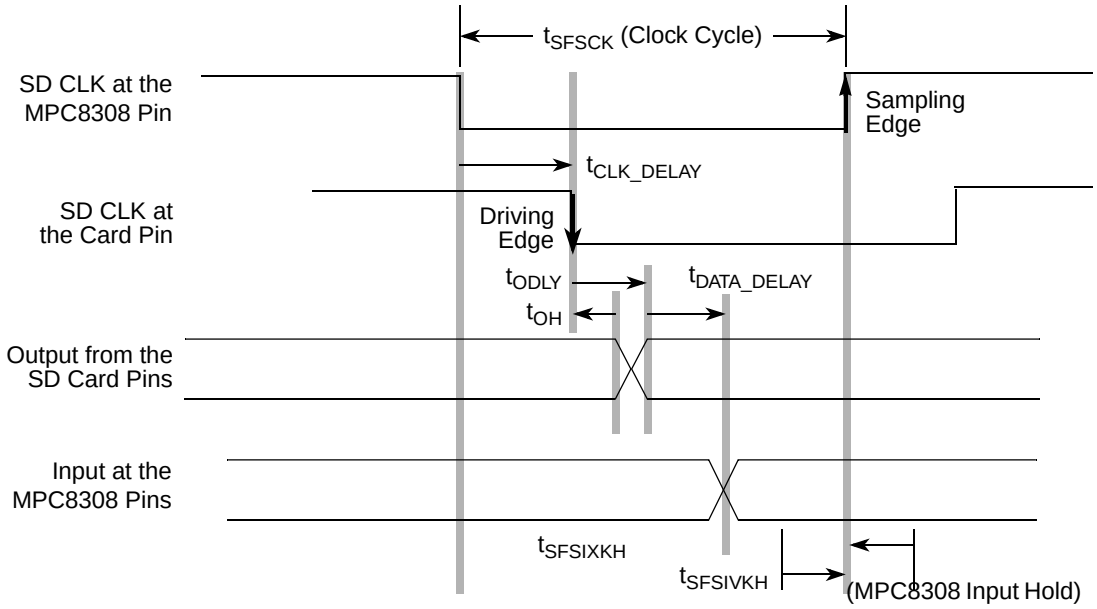


Figure 36. Full Speed Input Path

13.3 eSDHC AC Timing Specifications

This table provides the eSDHC AC timing specifications.

Table 40. eSDHC AC Timing Specifications for High Speed Mode

At recommended operating conditions NV_{DD} = 3.3 V ± 300 mV.

Parameter	Symbol [1]	Min	Max	Unit	Notes
SD_CLK clock frequency—high speed mode	f_{SHSCK}	0	50	MHz	3
SD_CLK clock cycle	t_{SHSCK}	20	—	ns	—
SD_CLK clock frequency—identification mode	f_{SIDCK}	0	400	kHz	—
SD_CLK clock low time	t_{SHSCKL}	7	—	ns	2
SD_CLK clock high time	t_{SHSCKH}	7	—	ns	2
SD_CLK clock rise and fall times	t_{SHSCKR}/ t_{SHSCKF}	—	3	ns	2
Input setup times: SD_CMD, SD_DATx	$t_{SHSIVKH}$	3	—	ns	2
Input hold times: SD_CMD, SD_DATx	$t_{SHSIXKH}$	2	—	ns	2
Output delay time: SD_CLK to SD_CMD, SD_DATx valid	$t_{SHSKHOV}$	3	—	ns	2
Output Hold time: SD_CLK to SD_CMD, SD_DATx invalid	$t_{SHSKHOX}$	–3	—	ns	2
SD Card Input Setup	t_{ISU}	6	—	ns	3
SD Card Input Hold	t_{IH}	2	—	ns	3

13.3.1 High Speed Output Path (Write)

This figure provides the data and command output timing diagram.

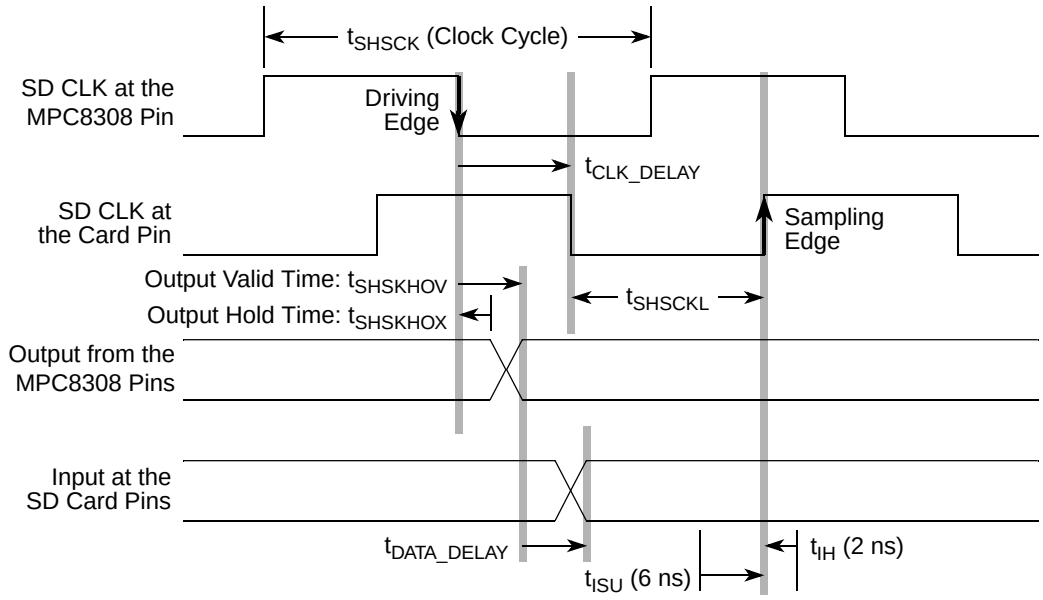


Figure 38. High Speed Output Path

13.3.2 High Speed Input Path (Read)

This figure provides the data and command input timing diagram.

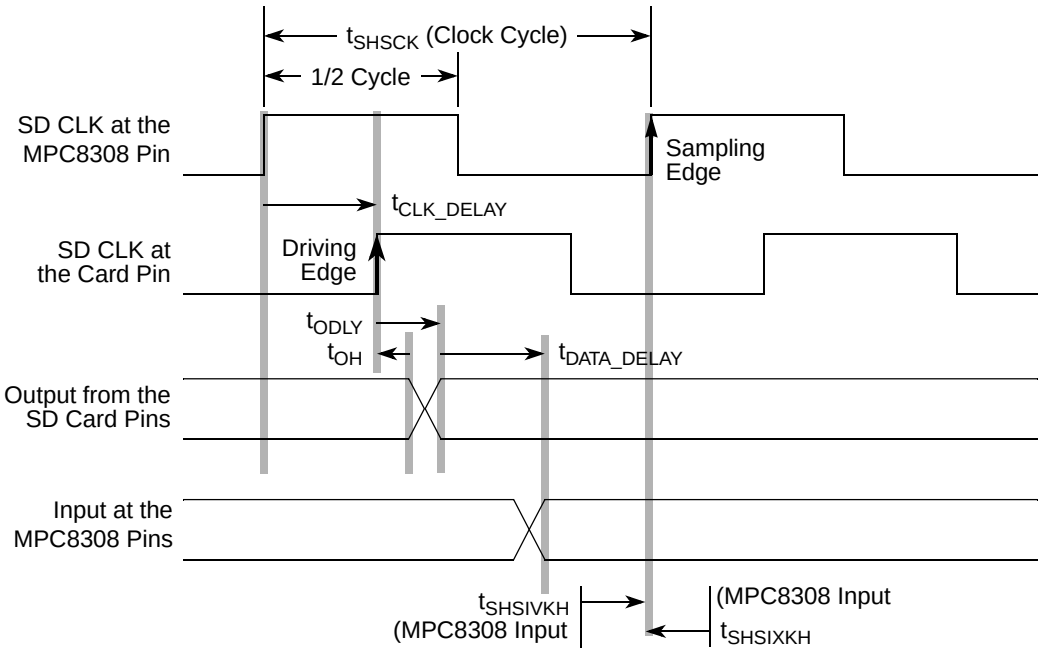


Figure 39. High Speed Input Path

Table 42. JTAG AC Timing Specifications (Independent of SYS_CLK_IN) [1] (continued)

At recommended operating conditions (see Table 2).

Parameter	Symbol[2]	Min	Max	Unit	Note
Output hold times: Boundary-scan data TDO	 t_{JTKLDX} t_{JTKLOX}	 2 2	 — —	ns	5
JTAG external clock to output high impedance: Boundary-scan data TDO	 t_{JTKLDZ} t_{JTKLOZ}	 2 2	 19 9	ns	5, 6

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of t_{TCLK} to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 40). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{JTDVKH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDXKH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
3. $\overline{\text{TRST}}$ is an asynchronous level sensitive signal. The setup time is for test purposes only.
4. Non-JTAG signal input timing with respect to t_{TCLK}.
5. Non-JTAG signal output timing with respect to t_{TCLK}.
6. Guaranteed by design and characterization.

This figure provides the AC test load for TDO and the boundary-scan outputs.

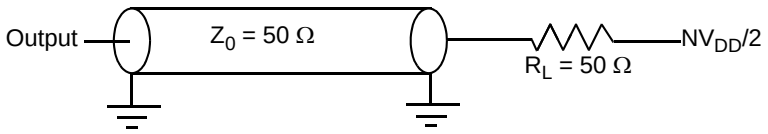


Figure 40. AC Test Load for the JTAG Interface

This figure provides the JTAG clock input timing diagram.

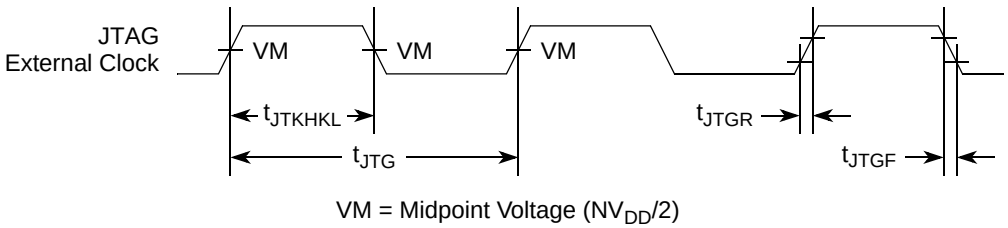


Figure 41. JTAG Clock Input Timing Diagram

15 I²C

This section describes the DC and AC electrical characteristics for the I²C interface.

15.1 I²C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I²C interface.

Table 43. I²C DC Electrical Characteristics

At recommended operating conditions with NV_{DD} of 3.3 V ± 0.3 V.

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times NV_{DD}$	$NV_{DD} + 0.3$	V	—
Input low voltage level	V_{IL}	–0.3	$0.3 \times NV_{DD}$	V	—
Low level output voltage	V_{OL}	0	$0.2 \times NV_{DD}$	V	1
High level output voltage	V_{OH}	$0.8 \times NV_{DD}$	$NV_{DD} + 0.3$	V	—
Output fall time from V_{IH}(min) to V_{IL}(max) with a bus capacitance from 10 to 400 pF	t_{I2KLKV}	$20 + 0.1 \times C_B$	250	ns	2
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	3
Capacitance for each I/O pin	C_I	—	10	pF	—
Input current, ($0 V \le V_{IN} \le NV_{DD}$)	I_{IN}	—	± 5	μA	—

Notes:
1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. C_B = capacitance of one bus line in pF.
3. For information on the digital filter used, see the *MPC8308 PowerQUICC II Pro Processor Reference Manual*.

15.2 I²C AC Electrical Specifications

This table provides the AC timing parameters for the I²C interface.

Table 44. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 43).

Parameter	Symbol[1]	Min	Max	Unit
SCL clock frequency	f_{I2C}	0	400	kHz
Low period of the SCL clock	t_{I2CL}	1.3	—	μs
High period of the SCL clock	t_{I2CH}	0.6	—	μs
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	μs
Data setup time	t_{I2DVKH}	100	—	ns
Data hold time: I²C bus devices	t_{I2DXKL}	— 0 [2]	— 0.9 [3]	μs
Fall time of both SDA and SCL signals[5]	t_{I2CF}	—	300	ns

Table 44. I²C AC Electrical Specifications (continued)

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 43).

Parameter	Symbol[1]	Min	Max	Unit
Setup time for STOP condition	t_{I2PVKH}	0.6	—	μs
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μs
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times NV_{DD}$	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times NV_{DD}$	—	V

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. The device provides a hold time of at least 300 ns for the SDA signal (referred to the V_{IHmin} of the SCL signal) to bridge the undefined region of the falling edge of SCL.
3. The maximum t_{I2DXKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. C_B = capacitance of one bus line in pF.
5. The device does not follow the *I²C-BUS Specifications, Version 2.1,* regarding the t_{I2CF} AC parameter.

This figure provides the AC test load for the I²C.

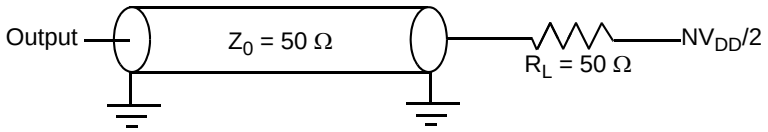


Figure 45. I²C AC Test Load

This figure shows the AC timing diagram for the I²C bus.

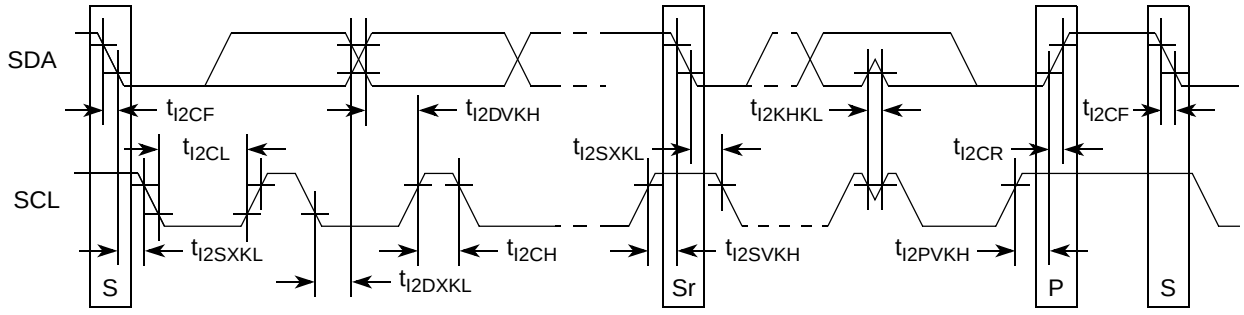


Figure 46. I²C Bus AC Timing Diagram

20.2 Mechanical Dimensions of the MPC8308 MAPBGA

This figure shows the mechanical dimensions and bottom surface nomenclature of the MAPBGA package.

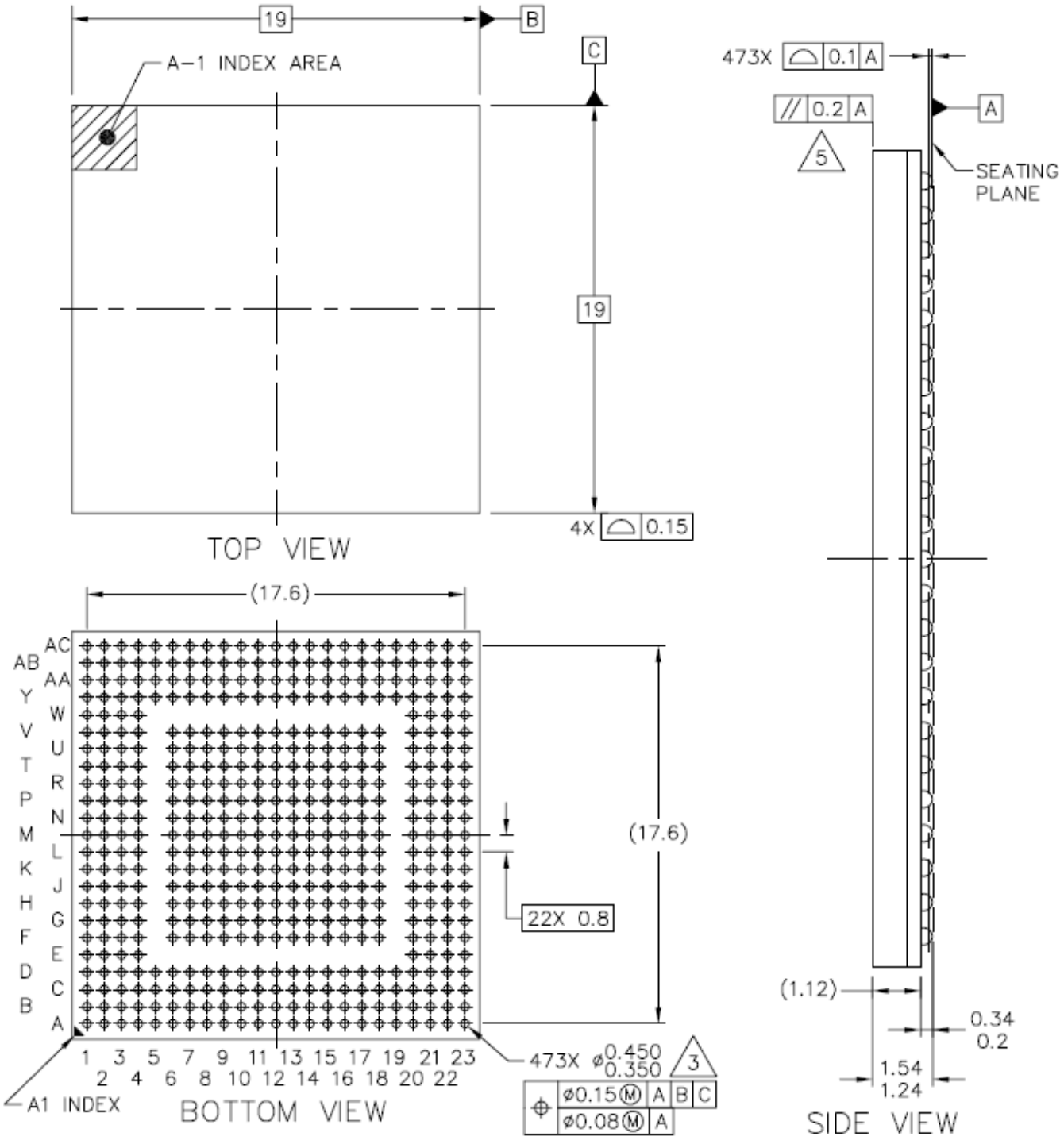


Figure 52. Mechanical Dimension and Bottom Surface Nomenclature of the MPC8308 MAPBG

Notes:
1. All dimensions are in millimeters.

2. Dimensions and tolerances per ASME Y14.5M-1994.
3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.

20.3 Pinout Listings

This table provides the pin-out listing for the MPC8308, MAPBGA package.

Table 53. MPC8308 Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Note
DDR Memory Controller Interface				
MEMC_MDQ[0]	V6	I/O	GV_{DDA}	—
MEMC_MDQ[1]	Y4	I/O	GV_{DDA}	—
MEMC_MDQ[2]	AB3	I/O	GV_{DDA}	—
MEMC_MDQ[3]	AA3	I/O	GV_{DDA}	—
MEMC_MDQ[4]	AA2	I/O	GV_{DDA}	—
MEMC_MDQ[5]	AA1	I/O	GV_{DDA}	—
MEMC_MDQ[6]	W4	I/O	GV_{DDA}	—
MEMC_MDQ[7]	Y2	I/O	GV_{DDA}	—
MEMC_MDQ[8]	W3	I/O	GV_{DDA}	—
MEMC_MDQ[9]	W1	I/O	GV_{DDA}	—
MEMC_MDQ[10]	Y1	I/O	GV_{DDA}	—
MEMC_MDQ[11]	W2	I/O	GV_{DDA}	—
MEMC_MDQ[12]	U4	I/O	GV_{DDA}	—
MEMC_MDQ[13]	U3	I/O	GV_{DDA}	—
MEMC_MDQ[14]	V4	I/O	GV_{DDA}	—
MEMC_MDQ[15]	U6	I/O	GV_{DDA}	—
MEMC_MDQ[16]	T3	I/O	GV_{DDB}	—
MEMC_MDQ[17]	T2	I/O	GV_{DDB}	—
MEMC_MDQ[18]	R4	I/O	GV_{DDB}	—
MEMC_MDQ[19]	R3	I/O	GV_{DDB}	—
MEMC_MDQ[20]	P4	I/O	GV_{DDB}	—
MEMC_MDQ[21]	N6	I/O	GV_{DDB}	—
MEMC_MDQ[22]	P2	I/O	GV_{DDB}	—
MEMC_MDQ[23]	P1	I/O	GV_{DDB}	—
MEMC_MDQ[24]	N4	I/O	GV_{DDB}	—
MEMC_MDQ[25]	N3	I/O	GV_{DDB}	—
MEMC_MDQ[26]	N2	I/O	GV_{DDB}	—

Table 53. MPC8308 Pinout Listing (continued)

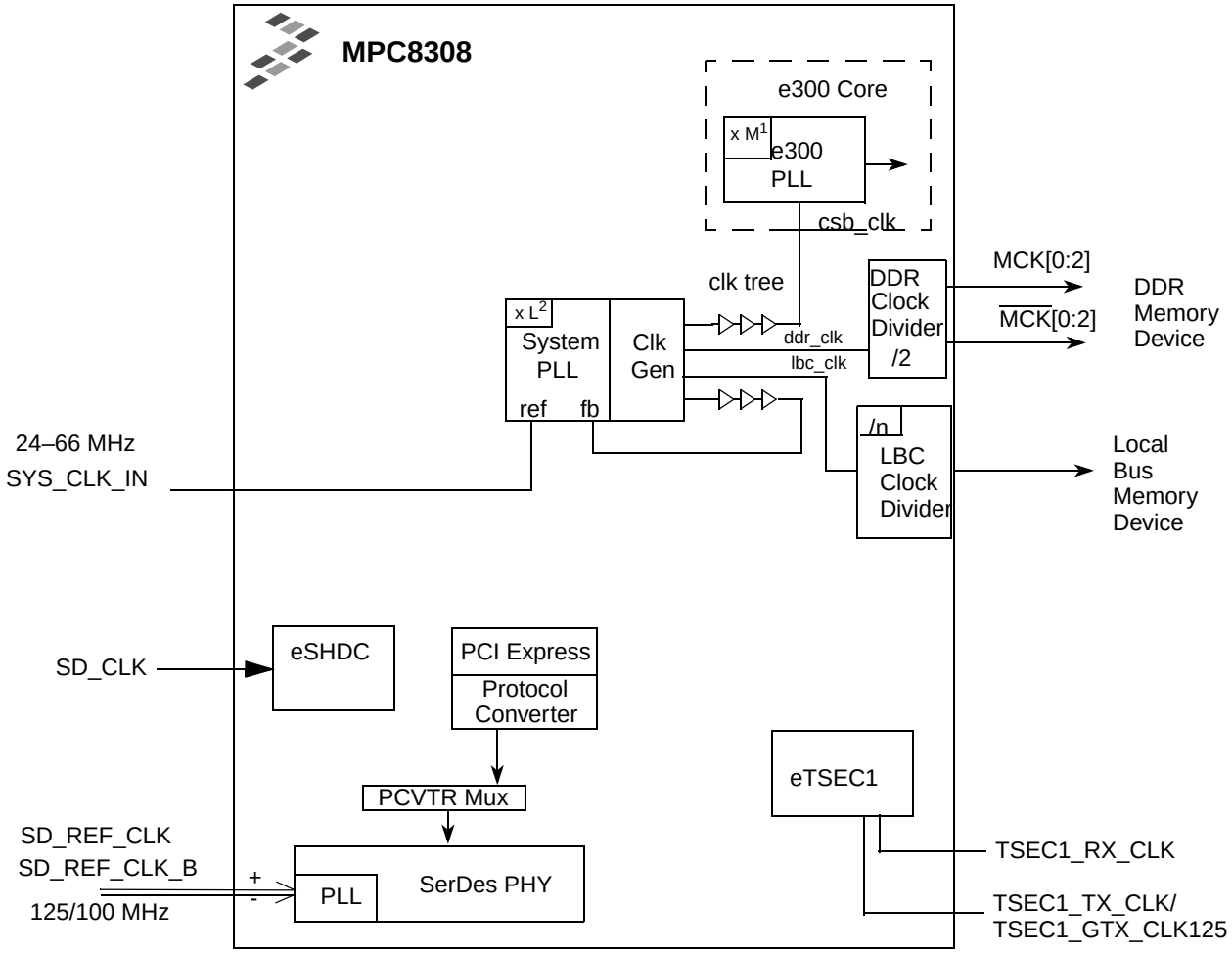
Signal	Package Pin Number	Pin Type	Power Supply	Note
$\overline{\text{LCS}}$[3]	Y11	O	NV_{DDP_K}	4
$\overline{\text{LWE}}$[0] /$\overline{\text{LFWE}}$0/$\overline{\text{LBS}}$0	AB11	O	NV_{DDP_K}	—
$\overline{\text{LWE}}$[1]/$\overline{\text{LBS}}$1	AC11	O	NV_{DDP_K}	—
LBCTL	U11	O	NV_{DDP_K}	—
LGPL0/LFCLE	Y10	O	NV_{DDP_K}	—
LGPL1/LFALE	AA10	O	NV_{DDP_K}	—
LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LFRE}}$	AB10	O	NV_{DDP_K}	4
LGPL3/$\overline{\text{LFWP}}$	AC10	O	NV_{DDP_K}	—
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT/ LFRB	AB9	I/O	NV_{DDP_K}	4
LGPL5	Y9	O	NV_{DDP_K}	—
LCLK0	AC12	O	NV_{DDP_K}	—
DUART				
UART_SOUT1/MSRCID0/ LSRCID0	C17	O	NV_{DDB}	—
UART_SIN1/MSRCID1/ LSRCID1	B18	I/O	NV_{DDB}	—
UART_SOUT2/MSRCID2/ LSRCID2	D17	O	NV_{DDB}	—
UART_SIN2/MSRCID3/ LSRCID3	D18	I/O	NV_{DDB}	—
PEX PHY				
TXA	C14	O	XPADVDD	—
$\overline{\text{TXA}}$	C15	O	XPADVDD	—
RXA	A13	I	XCOREVDD	—
$\overline{\text{RXA}}$	B13	I	XCOREVDD	—
SD_IMP_CAL_RX	A15	I	XCOREVDD	—
$\overline{\text{SD\_REF\_CLK}}$	C12	I	XCOREVDD	—
SD_REF_CLK	D12	I	XCOREVDD	—
SD_PLL_TPD	F13	O	—	—
SD_IMP_CAL_TX	A11	I	XPADVDD	—
SD_PLL_TPA_ANA	F11	O	—	—
SDAVDD_0	G12	I	—	—
SDAVSS_0	F12	I	—	—
I^2C interface				
IIC_SDA1	C9	I/O	NV_{DDA}	2

Table 53. MPC8308 Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Note
TSEC1_RXD[1]	C20	I	NV_{DDC}	—
TSEC1_RXD[0]	D20	I	NV_{DDC}	—
TSEC1_RX_ER	C23	I	NV_{DDC}	—
TSEC1_TX_CLK/ TSEC1_GTX_CLK125	E23	I	NV_{DDC}	—
TSEC1_TXD[3]/ CFG_RESET_SOURCE[0]	F22	I/O	NV_{DDC}	—
TSEC1_TXD[2]/ CFG_RESET_SOURCE[1]	F21	I/O	NV_{DDC}	—
TSEC1_TXD[1]/ CFG_RESET_SOURCE[2]	E21	I/O	NV_{DDC}	—
TSEC1_TXD[0]/ CFG_RESET_SOURCE[3]	D22	I/O	NV_{DDC}	—
TSEC1_TX_EN/ LBC_PM_REF_10	F20	O	NV_{DDC}	—
TSEC1_TX_ER/ LB_POR_CFG_BOOT_ECC	E22	I/O	NV_{DDC}	7
Ethernet Mgmt				
TSEC1_MDC	A20	O	NV_{DDB}	—
TSEC1_MDIO	C19	I/O	NV_{DDB}	2
eSDHC/GTM				
SD_CLK/GPIO[16]	D7	O	NV_{DDA}	—
SD_CMD/GPIO[17]	G9	I/O	NV_{DDA}	—
$\overline{\text{SD\_CD}}$/GTM1_TIN1/ GPIO[18]	A7	I	NV_{DDA}	—
SD_WP/$\overline{\text{GTM1\_TGATE1}}$/ GPIO[19]	D8	I	NV_{DDA}	—
SD_DAT[0]/$\overline{\text{GTM1\_TOUT1}}$/ GPIO[20]	C8	I/O	NV_{DDA}	—
SD_DAT[1]/$\overline{\text{GTM1\_TOUT2}}$/ GPIO[21]	B8	I/O	NV_{DDA}	—
SD_DAT[2]/GTM1_TIN2/ GPIO[22]	A8	I/O	NV_{DDA}	—
SD_DAT[3]/$\overline{\text{GTM1\_TGATE2}}$/ GPIO[23]	B9	I/O	NV_{DDA}	—
SPI				
SPIMOSI/MSRCID4/ LSRCID4	AB5	I/O	NV_{DDP_K}	—
SPIMISO/MDVAL/LDVAL	Y6	I/O	NV_{DDP_K}	—

21 Clocking

This figure shows the internal distribution of clocks within the device.



1 Multiplication factor M = 1, 1.5, 2, 2.5, and 3. Value is decided by RCWLR[COREPLL].

2 Multiplication factor L = 2, 3, 4, 5 and 6. Value is decided by RCWLR[SPMF].

Figure 53. MPC8308 Clock Subsystem

The following external clock sources are utilized on the MPC8308:

- System clock (SYS_CLK_IN)
- Ethernet Clock (TSEC1_RX_CLK/TSEC1_TX_CLK/TSEC1_GTX_CLK125 for eTSEC)
- SerDes PHY clock
- eSHDC clock (SD_CLK)

  For more information, see the SerDes chapter in the *MPC8308 PowerQUICC II Pro Processor Reference Manual*.

All clock inputs can be supplied using an external canned oscillator, a clock generation chip, or some other source that provides a standard CMOS square wave input.

23.3 Decoupling Recommendations

Due to large address and data buses, and high operating frequencies, the device can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the MPC8308 system, and the MPC8308 itself requires a clean, tightly regulated source of power. Therefore, it is recommended that the system designer place at least one decoupling capacitor at each V_{DD}, NV_{DD}, GV_{DD} and LV_{DD} pin of the device. These decoupling capacitors should receive their power from separate V_{DD}, NV_{DD}, GV_{DD}, LV_{DD}, and V_{SS} power planes in the PCB, utilizing short traces to minimize inductance. Capacitors may be placed directly under the device using a standard escape pattern. Others may surround the part.

These capacitors should have a value of 0.01 or 0.1 µF. Only ceramic SMT (surface mount technology) capacitors should be used to minimize lead inductance, preferably 0402 or 0603 sizes.

In addition, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD}, NV_{DD}, GV_{DD}, LV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They should also be connected to the power and ground planes through two vias to minimize inductance. Suggested bulk capacitors—100 to 330 µF (AVX TPS tantalum or Sanyo OSCON). However, customers should work directly with their power regulator vendor for best values and types of bulk capacitors.

23.4 Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. Unused active low inputs should be tied to NV_{DD}, GV_{DD}, LV_{DD} as required. Unused active high inputs should be connected to VSS. All NC (no-connect) signals must remain unconnected.

Power and ground connections must be made to all external V_{DD}, NV_{DD}, AV_{DD1}, AV_{DD2}, GV_{DD}, LV_{DD} and V_{SS} pins of the device.

23.5 Output Buffer DC Impedance

The device drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for I^2C, MDIO and HRESET)

To measure Z_0 for the single-ended drivers, an external resistor is connected from the chip pad to NV_{DD} or V_{SS}. Then, the value of each resistor is varied until the pad voltage is $NV_{DD}/2$ (Figure 55). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open), and R_P is trimmed until the voltage at the pad equals $NV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.